

# RELIABILITY REPORT



## RELIABILITY DATA

LT3011 LT3430/31/32/33/34/35/37/38/3800 LT4220 / LT4254/56 LT4356

6/1/2010

**• OPERATING LIFE TEST**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF <sup>(2)</sup> FAILURES
SOIC/SOT/MSOP	516	0329	0928	759.00	0
SSOP/TSSOP	725	0241	0711	725.00	0
QFN/DFN	304	0630	0818	405.64	0
	1,545			1,889.64	0

**• PRESSURE COOKER TEST AT 15 PSIG, +121°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	2,154	0146	0818	539.98	0
SSOP/TSSOP	5,895	0244	0911	634.89	0
	8,049			1,174.87	0

**• TEMP CYCLE FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	2,078	0146	0751	1,543.90	0
SSOP/TSSOP	5,942	0244	0910	2,234.85	0
QFN/DFN	44	0840	0840	4.40	0
	8,064			3,783.15	0

**• THERMAL SHOCK FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	1,362	0146	0818	1,199.11	0
SSOP/TSSOP	5,977	0244	0911	1,800.90	0
QFN/DFN	43	0840	0840	4.30	0
	7,382			3,004.31	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 0.97 FITS

(3) Mean Time Between Failures in Years = 117,605

Note: 1 FIT = 1 Failure in One Billion Hours.